

Search Notes

Application/Control No.

10/840,192

Examiner

EDMUND H. LEE

Applicant(s)/Patent under
Reexamination

FUJIKAWA ET AL.

Art Unit

1791

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
264	259,255	3/30/2009	EHL
264	319,293	3/30/2009	EHL
264/	220	3/30/2009	EHL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
264/259,255,319,293,220	3/30/2009	EHL
EAST	3/30/2009	EHL